Dual Precision Mono stable

General Description

The CD4538B is a dual, precision mono stable multi vibrator with independent trigger and reset controls. The device is re trigger able and reset table, and the control inputs are inter- nally latched. Two trigger inputs are provided to allow either rising or falling edge triggering. The reset inputs are active low and prevent triggering while active. Precise control of output pulse-width has been achieved using linear CMOS techniques. The pulse duration and accuracy are deter-mined by external components RX and CX. The device does not allow the timing capacitor to discharge through the tim- ing pin on power-down condition. For this reason, no exter-nal protection resistor is required in series with the timing pin. Input protection from static discharge is provided on all pins.



DIP-16



SOP-16



TSSOP-16

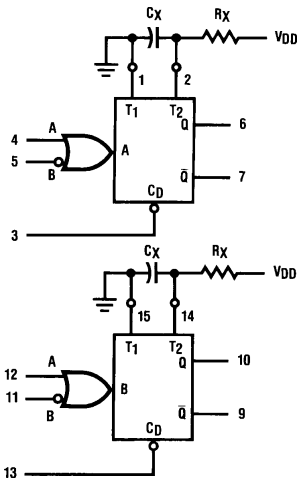
Features

- Wide supply voltage range:5.0V to 15V
- High noise immunity:0.45 V_{CC} (typ.)
- Low power TTL compatibility:Fan out of 2 driving 74L or 1 driving 74LS
- New formula: PW_{OUT} = RC (PW in seconds, R in Ohms, C in Farads)
- ±1.0% pulse-width variation from part to part (typ.)
- Wide pulse-width rang:1 μS to ∞
- Separate latched reset inputs
- Symmetrical output sink and source capability
- Low standby current:5 nA (typ.)@ 5 V_{DC}
- Pin compatible to CD4528B

Ordering Information

DEVICE	Package Type	MARKING	Packing	Packing Qty
CD4538BE/ CD4538BN	DIP-16	CD4538B	TUBE	1000pcs/box
CD4538BM/TR	SOP-16	CD4538B	REEL	2500pcs/reel
CD4538BMT/TR	TSSOP-16	CD4538B	REEL	2500pcs/reel

Block and Connection Diagrams

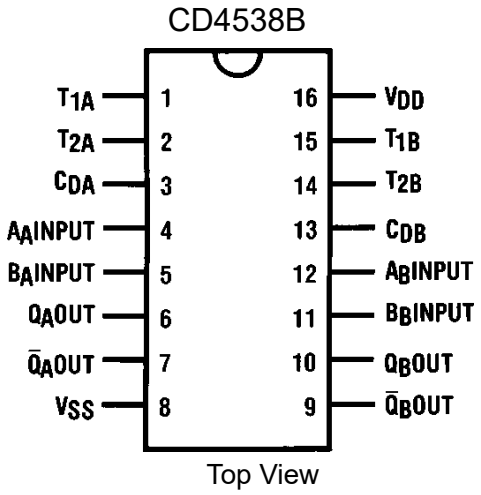


RX and CX are External Components

V_{DD}—Pin 16

V_{SS}—Pin 8

Dual-In-Line Package



Top View

Truth Table

Inputs			Outputs	
Clear	A	B	Q	Q
L	X	X	L	H
X	H	X	L	H
X	X	L	L	H
H	L	↓	⎍	⎎
H	↑	H	⎍	⎎

H= High Level L

L= Low Level

↑= Transition from Low to High

↓= Transition from High to Low

⎍= One High Level Pulse

⎎= One Low Level Pulse

X= Irrelevant

Maximum Ratings

Symbol	Parameter		Min	Max	Unit
V_{DD}	DC Supply Voltage		-0.5	+18	V_{DC}
V_{IN}	Input Voltage		-0.5	V_{DD}+0.5	V_{DC}
T_S	Storage Temperature Range		-65	+150	°C
P_D	Power Dissipation	Dual-In-Line	700		mW
		Small Outline	500		mW
T_L	Lead Temperature	Soldering, 10 seconds	260		℃

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed, they are not meant to imply that the devices should be operated at these limits. The tables of "Recommended Operating Conditions" and "Electrical Characteristics" provide conditions for acutal device operation.
Note 2: VSS e 0V unless otherwise specified.

Recommended Operating Conditions

Symbol	Parameter	Min	Max	Unit
V_{DD}	DC Supply Voltage	5	15	V_{DC}
V_{IN}	Input Voltage	0	V_{DD}	V_{DC}
T_A	Operating Temperature Range	-40	+85	°C

DC Electrical Characteristics

Symbol	Parameter	Conditions	-40°C		+25°C			+85°C		Units
			Min	Max	Min	Typ	Max	Min	Max	
IDD	Quiescent Device Current	VDD=5V VDD=10V VDD=15V VIH=VDD VIL=VSS All Outputs Open		20 40 80		0.005 0.010 0.015	20 40 80		150 300 600	μA
VOL	Low Level Output Voltage	VDD=5V VDD=10V VDD=15V |Iol|<1 μA VIH=VDD,ViL=Vss		0.05 0.05 0.05		0 0 0	0.05 0.05 0.05		0.05 0.05 0.05	V
VOH	High Level Output Voltage	VDD=5V VDD=10V VDD=15V |Iol|<1 μA VIH=VDD,ViL=Vss	4.95 9.95 14.95		4.95 9.95 14.95	5 10 15		4.95 9.95 14.95		V
VIL	Low Level Input Voltage	|Iol|<1 μA VDD=5V,VO=0.5V of 4.5V VDD=10V,VO=1.0V of 9.0V VDD=15V,VO=1.5V of 13.5V		1.5 3.0 4.0		2.25 4.50 6.75	1.5 3.0 4.0		1.5 3.0 4.0	V
VIH	High Level Input Voltage	|Iol|<1 μA VDD=5V,VO=0.5V of 4.5V VDD=10V,VO=1.0V of 9.0V VDD=15V,VO=1.5V of 13.5V	3.5 7.0 11.0		3.5 7.0 11.0	2.75 5.50 8.25		3.5 7.0 11.0		V
IOL	Low Level Output Current (Note 3)	VDD=5V,VO 0.4V VDD=10V,VO=0.5V VDD=15V,VO=1.5V VIH=VDD VIL=VSS	0.52 1.3 3.6		0.44 1.1 3.0	0.88 2.25 8.8		0.36 0.9 2.4		mA
IOH	High Level Output Current (Note 3)	VDD=5V,VO=4.6 VDD=10V,VO=9.5V VDD=15V,VO=13.5V VIL=VSS	-0.52 -1.3 -3.6		-0.44 -1.1 -3.0	-0.88 -2.25 -8.8		-0.36 -0.9 -2.4		mA
IIN	Input Current, Pin2 or 14	VDD=15V, VIN=0V or 15V		±0.02		$±10^{-5}$	±0.05		±0.5	μA
IIN	Input Current Other Inputs	VDD=15V, VIN=0V or 15V		±0.3		$±10^{-5}$	±0.3		±1.0	μA

Note 3: I_{OH} and I_{OL} are tested one output at a time.

AC Electrical Characteristics

* TA = 25°C, C_L= 50 pF, and tr= tf= 20 ns unless otherwise specified

Symbol	Parameter	Conditions		Min	Typ	Max	Units
t_{TLH}, t_{THL}	Output Transition Time	V_{DD}=5V V_{DD}=10V V_{DD}=15V			100 50 40	200 100 80	ns
t_{PLH}, t_{PHL}	Propagation Delay Time	Trigger Operation— A orB toQ orQ V_{DD}=5V V_{DD}=10V V_{DD}=15V Reset Operation— C_D toQ orQ V_{DD}=5V V_{DD}=10V V_{DD}=15V			 300 150 100 250 125 95	 600 300 220 500 250 190	 ns ns
t_{WL}, t_{WH}	Minimum Input Pulse Width A, B, or C_D	V_{DD}=5V V_{DD}=10V V_{DD}=15V			35 30 25	70 60 50	ns
t_{RR}	Minimum Retrigger Time	V_{DD}=5V V_{DD}=10V V_{DD}=15V			0	0 0 0	ns
C_{IN}	Input Capacitance	Pin 2 or 14 Other Inputs			10 5	 7.5	pF
PW_{OUT}	Output Pulse Width (Q or Q) (**Note**: For Typical Distribution, see Figure 9)	R_X=100 kΩ	V_{DD}=5V V_{DD}=10V V_{DD}=15V	208 211 216	226 230 235	244 248 254	μS
		R_X=100 kΩ C_X=0.1μF	V_{DD}=5V V_{DD}=10V V_{DD}=15V	8.83 9.02 9.20	9.60 9.80 10.00	10.37 10.59 10.80	ms
		R_X=100kΩ C_X=10.0 μF	V_{DD}=5V V_{DD}=10V V_{DD}=15V	0.87 0.89 0.91	0.95 0.97 0.99	1.03 1.05 1.07	S
Pulse Width Match between Circuits in the Same Package C_X=0.1 μF, R_X=100 kΩ		R_X=100 kΩ C_X=0.1 μF	V_{DD}=5V V_{DD}=10V V_{DD}=15V		±1 ±1 ±1		%
Operating Conditions							
R_X C_X	External Timing Resistance External Timing Capacitance			5.0 0		** No Limit	kΩ pF

Note 4:AC parameters are guaranteed by DC correlated testing.

Note 5:The maximum usable resistance R_X is a function of the leakage of the Capacitor C_X, leakage of the CD4538B, and leakage due to board layout, surface resistance, etc.

Logic Diagram

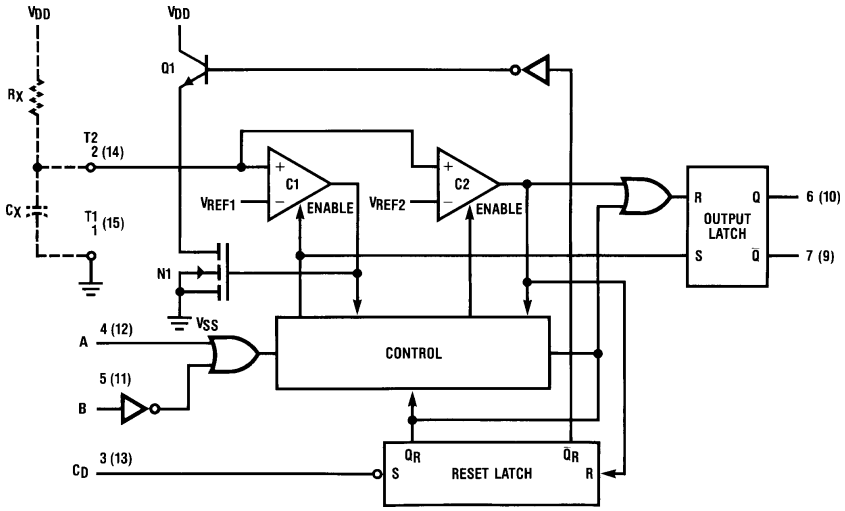
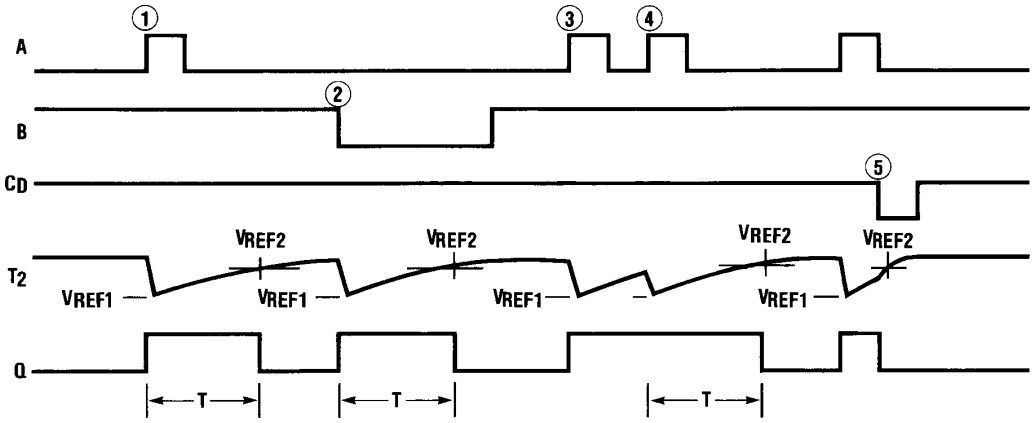


FIGURE 1

Theory of Operation



① POSITIVE EDGE TRIGGER
② NEGATIVE EDGE TRIGGER
③ POSITIVE EDGE TRIGGER
④ POSITIVE EDGE RE-TRIGGER (PULSE LENGTHENING)
⑤ RESET (PULSE SHORTENING)

FIGURE 2

Trigger Operation

The block diagram of the CD4538B is shown in Figure 1 , with circuit operation following.

As shown in Figures 1 and 2 , before an input trigger occurs, the monostable is in the quiescent state with the Q output low, and the timing capacitor C_X completely charged to V_{DD}. When the trigger input A goes from V_{SS} to V_{DD} (while inputs B and C_D are held to V_{DD}) a valid trigger is recog- nized, which turns on comparator C1 and N-Channel tran- sistor N1①. At the same time the output latch is set. With transistor N1 on, the capacitor C_X rapidly discharges toward V_{SS} until V_{REF1} is reached. At this point the output of com- parator C1 changes state and transistor N1 turns off. Com- parator C1 then turns off while at the same time comparator C2 turns on. With transistor N1 off, the capacitor C_X begins to charge through the timing resistor, RX, toward V_{DD}. When the voltage across C_X equals V_{REF2}, comparator C2 changes state causing the output latch to reset (Q goes low) while at the same time disabling comparator C2. This ends the timing cycle with the monostable in the quiescent state, waiting for the next trigger.

A valid trigger is also recognized when trigger input B goes from V_{DD} to V_{SS} (while input A is at VSS and input CD is at V_{DD})②.

It should be noted that in the quiescent state C_X is fully charged to V_{DD}, causing the current through resistor R_X to be zero. Both comparators are "off" with the total device current due only to reverse junction leakages. An added feature of the CD4538B is that the output latch is set via the input trigger without regard to the capacitor voltage. Thus, propagation delay from trigger to Q is independent of the value of C_X, R_X, or the duty cycle of the input waveform.

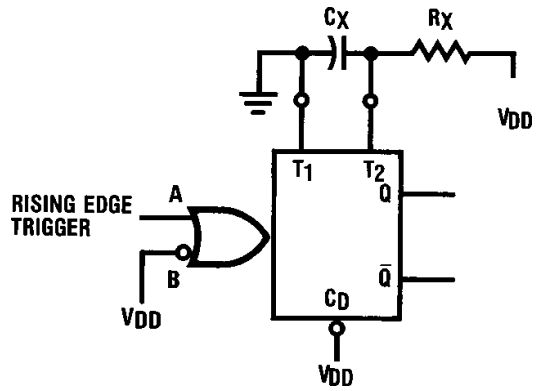
Retrigger Operation

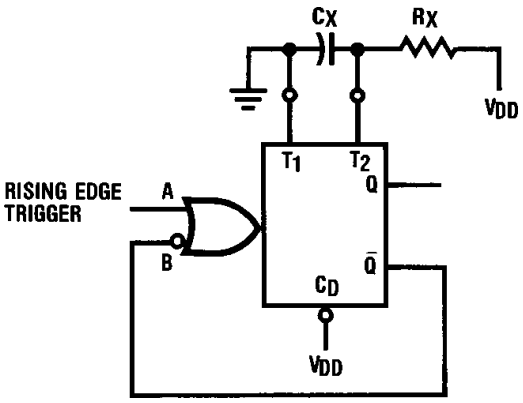
The CD4538B is retriggered if a valid trigger occurs ③ fol lowed by another valid triggerm ④ before the Q output has returned to the quiescent (zero) state. Any retrigger, after the timing node voltage at pin 2 or 14 has begun to rise from V_{REF1}, but has not yet reached V_{REF2}, will cause an in crease in output pulse width T. When a valid retrigger is initiatedm④, the voltage at T2 will again drop to V_{REF1} before progressing along the RC charging curve toward V_{DD}. The Q output will remain high until time T, after the last valid retrigger.

Reset Operation

The CD4538B may be reset during the generation of the output pulse. In the reset mode of operation, an input pulse on C_D sets the reset latch and causes the capacitor to be fast charged to V_{DD} by turning on transistor Q1⑤. When the voltage on the capacitor reaches V_{REF2}, the reset latch will clear and then be ready to accept another pulse. If the C_D input is held low, any trigger inputs that occur will be inhibited and the Q and $\overline{Q}$ outputs of the output latch will not change. Since the Q output is reset when an input low level is detected on the C_D input, the output pulse T can be made significantly shorter than the minimum pulse width specification

Typical Applications





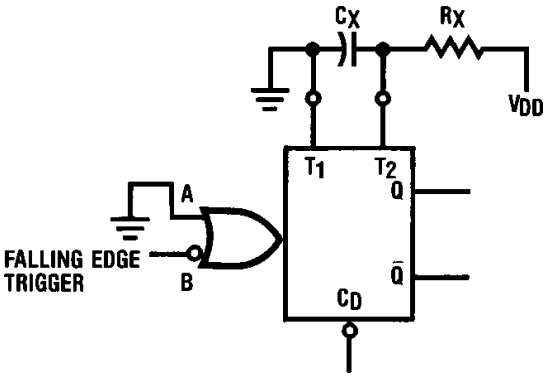


FIGURE 3. Retriggerable Monostables Circuitry

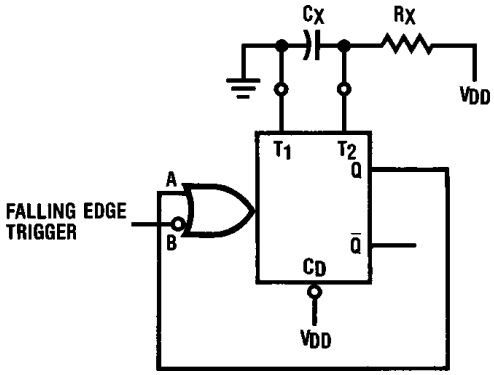


FIGURE 4. Non-Retriggerable Monostables Circuitry

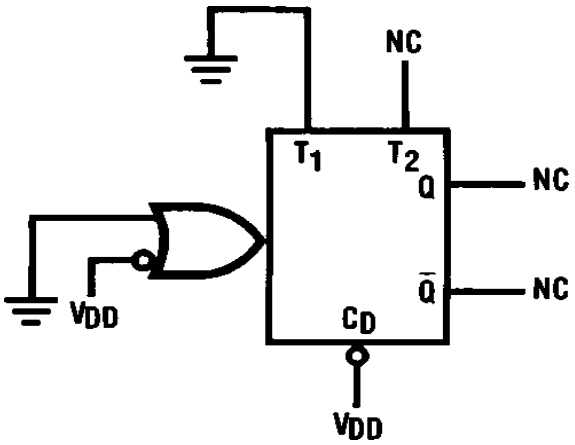


FIGURE 5. Connection of Unused Sections

Typical Applications

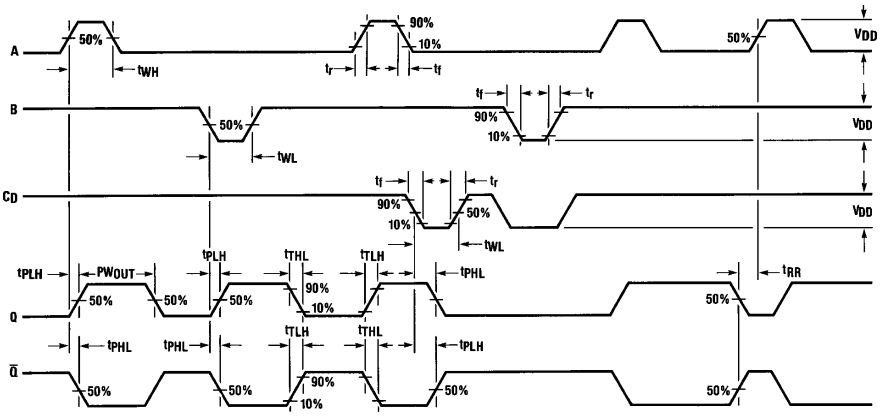
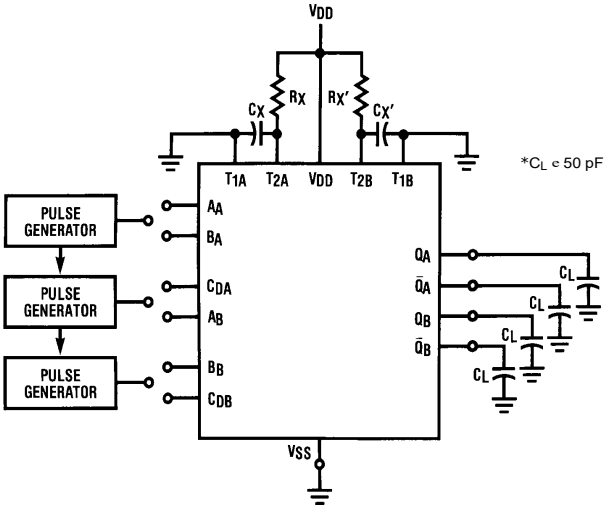
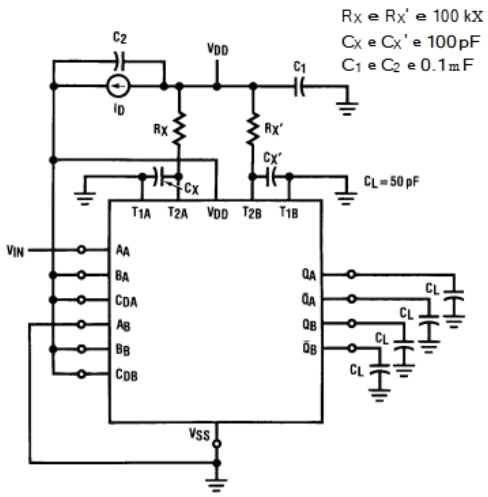


FIGURE 6. Switching Test Waveforms





Input Connections

Characteristics	CD	A	B
t_{PLH}, t_{PHL}, t_{TLH}, t_{THL} PW_{OUT}, t_{WH}, t_{WL}	V_{DD}	PG1	V_{DD}
t_{PLH}, t_{PHL}, t_{TLH}, t_{THL} PW_{OUT}, t_{WH}, t_{WL}	V_{DD}	V_{SS}	PG2
$t_{PLH(R)}$, $t_{PHL(R)}$, t_{WH}, t_{WL}	PG3	PG1	PG2

*Includes capacitance of probes, wiring, and fixture parasitic
Note: Switching test waveforms for PG1, PG2, PG3 are shown in *Figure 6*.

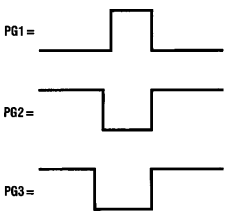
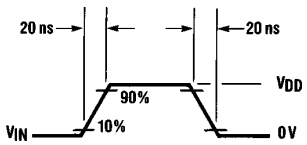


FIGURE 7. Switching Test Circuit



Duty Cycle = 50%

FIGURE8.Power Dissipation Test Circuit and Waveforms

Typical Applications

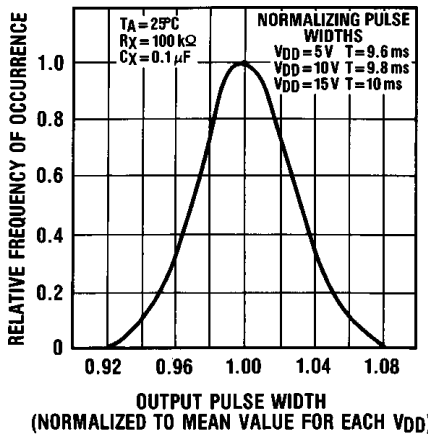


FIGURE 9. Typical Normalized Distribution of Units for Output Pulse Width

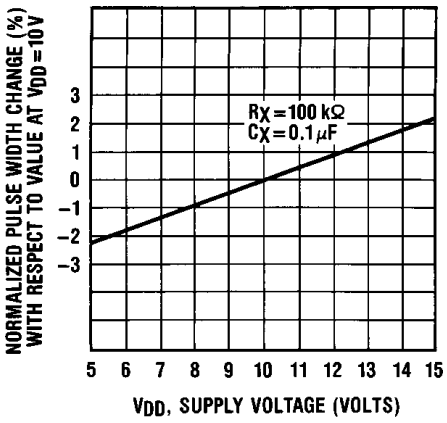


FIGURE 10. Typical Pulse Width Variation as a Function of Supply Voltage V_{DD}

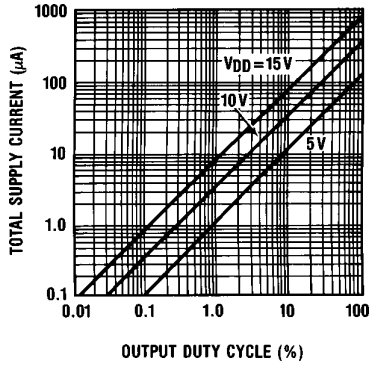


FIGURE 11. Typical Total Supply Current VersusFIGURE Output Duty Cycle, R_X = 100 kΩ, C_L = 50 pF, C_X = 100 pF, One Monostable Switching Only

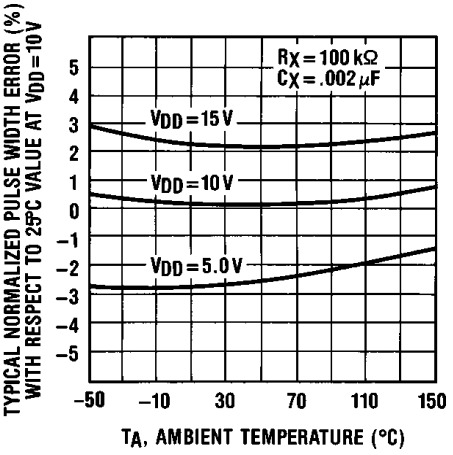


FIGURE 12. Typical Pulse Width Error Versus Temperature

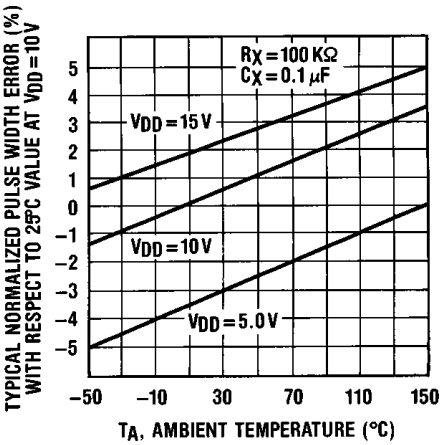


FIGURE 13. Typical Pulse Width Error Versus Temperature

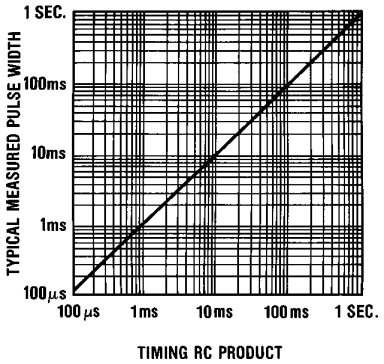
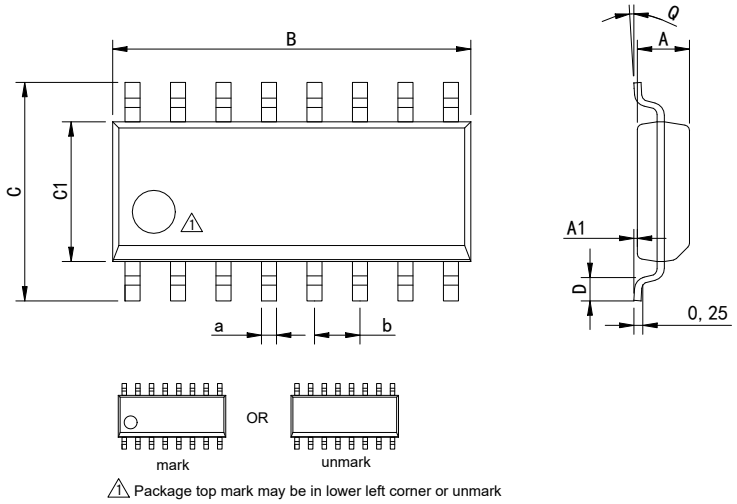


FIGURE 14. Typical Pulse Width Versus Timing RC Product

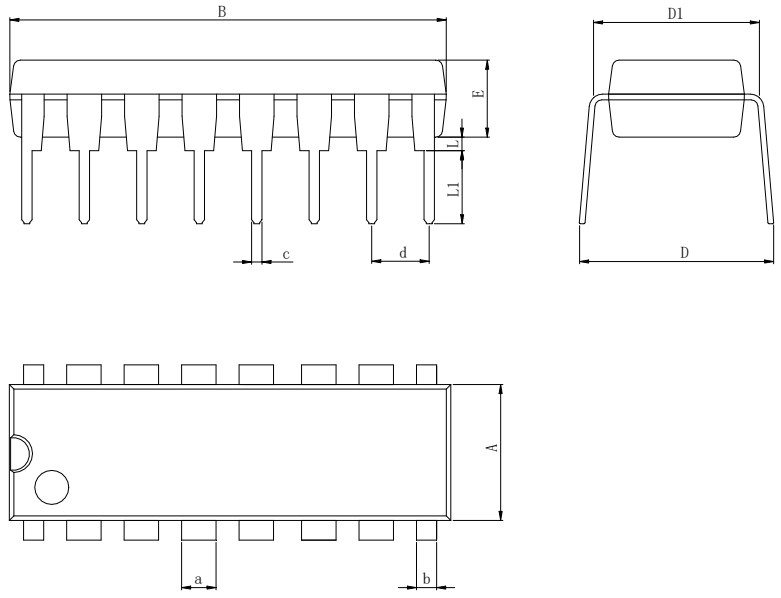
Physical Dimensions

SOP-16



Dimensions In Millimeters(SOP-16)									
Symbol:	**A**	**A1**	**B**	**C**	**C1**	**D**	**Q**	**a**	**b**
Min:	1.35	0.05	9.80	5.80	3.80	0.40	0°	0.35	1.27 BSC
Max:	1.55	0.20	10.0	6.20	4.00	0.80	8°	0.45	

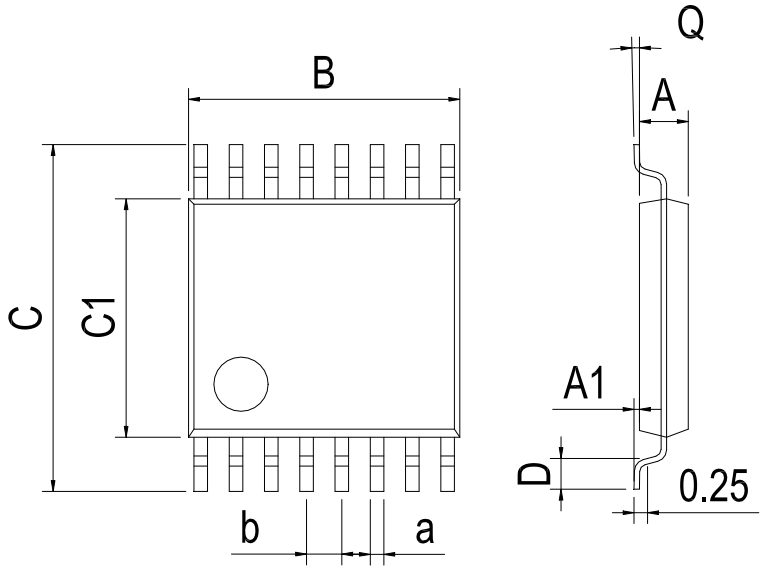
DIP-16



Dimensions In Millimeters(DIP-16)											
Symbol:	A	B	D	D1	E	L	L1	a	b	c	d
Min:	6.10	18.94	8.10	7.42	3.10	0.50	3.00	1.50	0.85	0.40	2.54 BSC
Max:	6.68	19.56	10.9	7.82	3.55	0.70	3.60	1.55	0.90	0.50	

Physical Dimensions

TSSOP-16



Dimensions In Millimeters(TSSOP-16)									
Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	0.85	0.05	4.90	6.20	4.30	0.40	0°	0.20	0.65 BSC
Max:	0.95	0.20	5.10	6.60	4.50	0.80	8°	0.25	

Revision History

REVISION NUMBER	DATE	REVISION	PAGE
V1.0	2015-5-7	New	1-13
V1.1	2018-9	Modify the package dimension diagram TSSOP-16、Updated DIP-16 dimension	10、11
V1.2	2021-8	Update encapsulation type、Update DIP Package New Model	1
V1.3	2024-10	Update Lead Temperature	3
V1.4	2025-11	Update important statements、Update SOP-16 Dimension drawing	10、13

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